This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

- 1. (Currently Amended) The A method of claim 49 wherein the property determined is for counting a set of tags, each tag having at least one resonant element, the method comprising:
 - (a) having at least one reference resonant frequency; ω₀, common to the tags;
 - (b) measuring the resulting resonant frequency, ω, of the set of interacting tags; and
 - (e) determining the number of tags in the set, n, using the measured frequency and the reference frequency.
- 2. (Original) The method of claim 1 wherein the reference resonant frequency is measured.
- 3. (Original) The method of claim 1 wherein the reference resonant frequency is computed from at least one of the known geometry and the physical dimensions of a tag.
- 4. (Original) The method of claim 1 wherein each tag comprises one or more resonant elements.
- 5. (Original) The method of claim 1 wherein each tag is identical to the other tags of the set.
- 6. (Original) The method of claim 1 wherein the set of tags comprises multiple subsets of resonant elements, each subset of resonant elements having its own resonant frequency.
 - 7. (Original) The method of claim 1 wherein each tag is affixed to a movable object.
 - (Original) The method of claim 1 wherein the set of tags is arranged in a stack.
- 9. (Original) The method of claim 8 wherein pairs of adjacent tags in the stack have a substantially equal spacing.

- 10. (Original) The method of claim 1 wherein n is a monotonic function of the measured resonant frequency.
- 11. (Original) The method of claim 1 wherein each tag present has an inductance, L, and the number of tags present is given by a value substantially equal to $\sqrt{\frac{L^2(\omega^2 \omega_0^2)}{\omega^2 M^2}} + 1$, where M is the mutual inductance between the individual tags.
- 12. (Original) The method of claim 1 wherein the reference frequency is provided as a regression-fit function to a plurality of empirical measurements of the number of tags in a test set and the resonant frequency of the test set.
- 13. (Original) The method of claim 1 wherein the reference frequency is provided as a value determined from at least one measurement of a single tag.
- 14. (Original) The method of claim 1 wherein the reference frequency is provided as a value determined from at least one measurement of a plurality of tags.
- 15. (Original) The method of claim 1 wherein the reference frequency is provided as a value computed from the known geometry and dimensions of each tag in the set.
- 16. (Currently Amended) The A method of claim 49 wherein the property determined is for determining a separation between a pair of tags, each tag having at least one resonant element, the method comprising:
 - (a) having at least one reference resonant-frequency, ω₀, common to the tags;
 - (b) measuring the resulting resonant frequency, ω, of the pair of interacting tags; and
 - (e) determining the separation between the a pair of tags in the set using the measured frequency and the reference frequency.
 - 17. (Original) The method of claim 16 wherein the separation is a lateral distance.
 - 18. (Original) The method of claim 16 wherein the separation is an axial distance.
- 19. (Original) The method of claim 16 wherein each tag is affixed to a movable object.

- 20. (Original) The method of claim 16 wherein the reference frequency is provided as a regression-fit function to a plurality of empirical measurements of the separation between a test pair of tags and the resonant frequency of the test pair.
- 21. (Original) The method of claim 16 wherein the reference frequency is provided as a value determined from at least one measurement of a single tag.
- 22. (Original) The method of claim 16 wherein the reference frequency is provided as a value determined from at least one measurement of a plurality of tags.
- 23. (Original) The method of claim 16 wherein the reference frequency is provided as a value computed from known parameters of a resonant element in the set.
- 24. (Original) The method of claim 16 wherein determining the separation comprises determining the mutual inductance between the pair of tags and determining the separation using the mutual inductance.
- 25. (Currently Amended) The An apparatus of claim 50 wherein the property determined is for counting a set of tags, each tag having at least one resonant element, the apparatus comprising:

a source providing at least one reference resonant frequency, ω_0 , common to all tage; a sensor for measuring the resultant resonant frequency, ω , of the set of interacting tage; a computational element-for determining the number of tags in the set, n, using the measured frequency and the reference frequency.

- 26. (Original) The apparatus of claim 25 wherein the reference resonant frequency is measured.
- 27. (Original) The apparatus of claim 25 wherein the reference resonant frequency is computed from at least one of the known geometry and the physical dimensions of a tag.
- 28. (Original) The apparatus of claim 25 wherein each tag comprises one or more resonant elements.

- 29. (Original) The apparatus of claim 25 wherein each tag is identical to the other tags of the set.
- 30. (Original) The apparatus of claim 25 wherein the set of tags comprises multiple subsets of resonant elements, with each subset of resonant elements having its own resonant frequency.
- 31. (Original) The apparatus of claim 25 wherein each tag is affixed to a movable object.
- 32. (Original) The apparatus of claim 25 wherein the set of tags is arranged in a stack.
- 33. (Original) The apparatus of claim 32 wherein pairs of adjacent tags in the stack have a substantially equal spacing.
- 34. (Original) The apparatus of claim 25 wherein n is a monotonic function of the measured resonant frequency.
- 35. (Original) The apparatus of claim 25 wherein each tag present has an inductance, L, and the number of tags present is given by a value substantially equal to $\sqrt{\frac{L^2(\omega^2 \omega_0^2)}{\omega^2 M^2}} + 1$, where M is the mutual inductance between the individual tags.
- 36. (Original) The apparatus of claim 25 wherein the reference frequency is provided as a regression-fit function to a plurality of empirical measurements of the number of tags in a test set and the resonant frequency of the test set.
- 37. (Original) The apparatus of claim 25 wherein the reference frequency is provided as a value determined from at least one measurement of a single tag.
- 38. (Original) The apparatus of claim 25 wherein the reference frequency is provided as a value determined from at least one measurement of a plurality of tags.

- 39. (Original) The apparatus of claim 25 wherein the reference frequency is provided as a value computed from known parameters of a resonant element in the set.
- 40. (Currently Amended) The An apparatus of claim 50 wherein the property determined is for determining a separation between a pair of tags, the apparatus comprising: a source providing at least one reference resonant frequency, ω₀, common to the tags; a sensor for measuring the resulting resonant frequency, ω, of the pair of interacting tags; and
 - a computational element for determining the separation between the a pair of tags in the set using the measured frequency and the reference frequency.
 - 41. (Original) The apparatus of claim 40 wherein the separation is a lateral distance.
 - 42. (Original) The apparatus of claim 40 wherein the separation is an axial distance.
- 43. (Original) The apparatus of claim 40 wherein each tag is affixed to a movable object.
- 44. (Original) The apparatus of claim 40 wherein the reference frequency is provided as a regression-fit function to a plurality of empirical measurements of the separation between a test pair of tags and the resonant frequency of the test pair.
- 45. (Original) The apparatus of claim 40 wherein the reference frequency is provided as a value determined from at least one measurement of a single tag.
- 46. (Original) The apparatus of claim 40 wherein the reference frequency is provided as a value determined from at least one measurement of a plurality of tags.
- 47. (Original) The apparatus of claim 40 wherein the reference frequency is provided as a value computed from known parameters of a resonant element in the set.
- 48. (Original) The apparatus of claim 40 wherein the computational element determines the mutual inductance between the pair of tags and determines the separation using the mutual inductance.

- 49. (New Claim) A method for determining at least one property of a set of tags, each tag having at least one resonant element, the method comprising:
 - (a) having at least one reference frequency, ω_0 , common to the tags;
 - (b) measuring the resulting resonant frequency, ω , of the set of interacting tags; and
 - (c) determining the property using the measured frequency and the reference frequency.
- 50. (New Claim) An apparatus for determining at least one property of a set of tags, each tag having at least one resonant element, the apparatus comprising:
 - (a) a source providing at least one reference frequency, ω_0 , common to the tags;
 - (b) a sensor for measuring the resulting resonant frequency, ω , of the set of interacting tags; and
 - (c) a computational element for determining the property using the measured frequency and the reference frequency.